Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/627,536	BAKER, R. JACOB
Examiner	Art Unit
Paul Dinh	2825

SEARCHED				
Class	Subclass	Date	Examiner	
327	52-58	2/16/2005	PD	
327	65	2/16/2005	PD	
327	108	2/16/2005	PD	
327	112	2/16/2005	PD	
327	560	2/16/2005	PD	
327	563	2/16/2005	PD	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
Search	above	2/18/2005	PD		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST, IEEE	2/16/2005	PD	
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